MEDIATEK Inc.

RECIPIENT

SPECIFICATIONS

Product No.: X1G004211000300

TG-5006CG-12H model : 26MHz

SPEC. No. : A12-1026-0B

DATE: Mar. 29. 2013

SEIKO EPSON CORPORATION

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SPECIFICATIONS

1. Application

This document is applicable to the temperature compensated crystal oscillator (TCXO) that is delivered to **MEDIATEK Inc.** from SEIKO EPSON Corp.

This product is compliant with RoHS Directive.

This Product supplied (and any technical information furnished, if any) by SEIKO EPSON Corp. shall not be used for the development and manufacture of weapon of mass destruction or for other military purposes.

Making available such products and technology to any third party who may use such products or technologies for the said purposes are also prohibited.

This product listed here is designed as components or parts for electronics equipment in general consumer use.

We do not expect that any of these products would be incorporated or otherwise used as a component or part for the equipment, which requires an extra high reliability, such as satellite, rocket and other space systems, and medical equipment, the functional purpose of which is to keep life.

2.Model

The product No. of this crystal oscillator unit is X1G004211000300. The model is TG-5006CG-12H (TCXO)

3. Packing

It is subject to the packing standard of SEIKO EPSON Corp.

4. Amendment and abolishment

Amendment and/or abolishment of this specification are subject to the agreement of both parties.

5.Contents

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6 Moisture Sensitivity

MSL level :2a

[1] Characteristics

- \bullet Lead Free Reflowable and ultra small SMD(2.5 \times 2.0 \times 0.9 mm).
- Using the heat-resisting type AT cut quartz crystal allows almost the same temperature soldering as universal SMD IC.
- \bullet Operating supply voltage: V_{CC}1 : 1.8 V, V_{CC}2 : 2.8 V

[2] Absolute maximum ratings

| Parameter | Symbol | Value | Unit | Note |
|---------------------------|----------------------|-------------|------|------|
| Supply voltage | V _{cc} -GND | -0.3 to 4.0 | V | |
| Storage temperature range | T_stg | -40 to +85 | °C | |

[3] Operating range

| Parameter | | Symbol | | Value | | Linit | Noto | |
|-----------------------------|------------------|-------------------|------|-------|------|-------|------------------------|--|
| | | Symbol | Min. | Тур. | Max. | Unit | Note | |
| Power v | voltage | V _{CC} 1 | 1.70 | 1.80 | 1.90 | V | $V_{CC}=1.8~V\pm0.10V$ | |
| | | V _{CC} 2 | 2.52 | 2.80 | 3.08 | V | $V_{CC}=2.8~V\pm0.28V$ | |
| Power voltage | | GND | 0.0 | 0.0 | 0.0 | V | | |
| Operating temperature range | | T_use | -40 | +25 | +85 | °C | | |
| Output load | | Load_R | 9 | 10 | 11 | kΩ | | |
| | | Load_C | 9 | 10 | 11 | pF | | |
| | DC-cut capacitor | C _C | 0.01 | | | μF | | |

DC-cut capacitor is not included in our TCXO. Please insert DC-cut capacitor(0.01uF Min.) in output line.

[4] Frequency characteristics

1) Output frequency 26.00000 MHz

2) Frequency characteristics

(Condition : $V_{CC}1$: 1.8 V / $V_{CC}2$: 2.8 V, GND = 0.0 V, Load 10 k Ω // 10 pF, T_use =+25 °C)

| Parameter | Symbol | ol Value | | Note |
|------------------------------------|----------------------|--|-----|--|
| Eroquency telerance | f_tol(osc) | \pm 0.8 × 10 ⁻⁶ Max. | - | T_use =+25 °C ± 2 °C Before Reflow |
| Frequency tolerance | f-osc | \pm 2.0 \times 10 $^{\text{-6}}$ Max. *1 | - | T_use =+25 °C ± 2 °C Reflow cycle : 2times *2 |
| Frequency / temperature | f To | \pm 0.5 \times 10 $^{\text{-6}}$ Max. | - | T_use =- 30 °C to + 85 °C (Based on frequency at +25 °C) |
| characteristics | 1 ₀ -1C | \pm 3.0 \times 10 $^{\text{-6}}$ Max. | - | T_use =- 40 °C to - 30 °C (Based on frequency at +25 °C) |
| | | \pm 0.05 \times 10 $^{\text{-6}}$ Max. | | T_use =- 20 °C to + 65 °C |
| Frequency slope vs. Temp. | f₀-Tc/°C | \pm 0.10 \times 10 $^{\text{-6}}$ Max. | /°C | T_use =- 30 °C to + 85 °C |
| | | \pm 0.35 \times 10 $^{\text{-6}}$ Max. | | T_use =- 40 °C to - 30 °C |
| Static temperature hysteresis | | \pm 0.6 \times 10 ⁻⁶ Max. | | Temp.ramped over operating range. Frequency measured before and after at +25 *C |
| Frequency / Load coefficient | f ₀ -Load | \pm 0.1 \times 10 $^{-6}$ Max. | - | Load : 10 k Ω // 10 pF \pm 10 % each |
| Frequency / voltage coefficient | f_0 - V_{CC} | \pm 0.1 \times 10 $^{\text{-6}}$ Max. | - | V_{cc} 1 = 1.80 V ± 0.10 V V_{cc} 1 = 2.80 V ± 0.28 V |
| | | \pm 1.0 \times 10 $^{\text{-6}}$ Max. | - | T_use =+25 °C first year |
| Frequency aging | fago | \pm 1.5 \times 10 ⁻⁶ Max. | - | T_use =+25 °C 2 years |
| | i_aye | \pm 2.5 \times 10 ⁻⁶ Max. | - | T_use =+25 °C 5 years |
| | | \pm 5.0 \times 10 ⁻⁶ Max. | - | T_use =+25 °C 10 years |

*1 Include initial frequency tolerance and frequency deviation after reflow cycles.

*2 Measurement of frequency deviation is made 1h after reflow soldering.

| | | | _ | | |
|------------|---------------------------------|------------------|----------------------------|-------------------------|--------------------------|
| (Condition | $1 \cdot 1 = 1 \cdot 1 \cdot 2$ | \//\/ | / CND = 0.0 V / 1.000 | 10k0//10pE T | $c_{0} = \pm 25 \circ C$ |
| | I. VCCI. I.O | V / VCCZ . Z.O V | V_{1} GIND – 0.0 V, LUAU | $10 \times 2 / 10 \mu$ | 3C - TZJ U / |

| Parameter | Symbol | Symbol Value | | | Unit | Note | |
|---------------------|-----------------|--------------|------|------|----------------|---|--|
| T diameter | Cymbol | Min. | Тур. | Max. | Onic | THOICE . | |
| Current consumption | I _{cc} | - | - | 1.5 | mA | | |
| Output level | V _{PP} | 0.8 | - | 1.5 | V | Peak to peak Clipped sinewave | |
| Summetry | SVM | 40 | - | 60 | 0/ | T_use =-30°C to +85°C, GND level | |
| Symmetry | STIVI | 45 | - | 55 | 70 | T_use =+25°C, GND level | |
| Harmonics | - | - | - | -8 | dBc | All harmonics | |
| | + | - | - | 2.0 | | Until freqency has been reached within ± 0.5 ppm of final freqency. | |
| Start up time | LOSC | | | 2.0 | 1115 | Until output signal has been reached min90% of final amp. | |
| | | - | - | -50 | | Offset:1 Hz | |
| | | - | - | -80 | | Offset:10 Hz | |
| SSP Dhase noise | L (f) | - | - | -105 | dBc | Offset:100 Hz | |
| SSB Phase hoise | L(f) | - | - | -130 | /Hz | Offset:1 KHz | |
| | | - | - | -148 | | Offset:10 kHz | |
| | | 150 | | | Offset:100 KHz | | |

[6] Test circuit

1) Output Load



Impossible to measure both frequency and wave form at the same time.(In case of using oscilloscope's amplifier output, possible to measure both at the same time.)

- 2. CL includes probe capacitance.
- 3. A capacitor (By-pass:0.01 $\,\mu\text{F})$ is placed between V_{CC} and GND,and closely to TCXO.
- 4. Use the current meter whose internal impedance value is small.
- 5. Power Supply

Impedance of power supply should be as lowest as possible.

6. GND should apply one point earth.

[7] Environmental and mechanical characteristics

| | | Valu | ie *1 | | | |
|-----|--|--|--|---|--|--|
| No. | Item | Freq. ToleranceElectrical[1×10 ⁻⁶] *2characteristics | | Test method | | |
| 1 | High temp. storage *3 | ± 2.0 | | +85 °C × 1 000 h | | |
| 2 | Low temp. storage *3 | ± 2.0 | | -40 °C × 1 000 h | | |
| 3 | High temperature with Humidity | ± 2.0 | | +85 ± 2 °C × 85 ± 5 %RH × 1 000 h | | |
| 1 | Tomp cyclo *2 | +20 | | -40 °C to +85 °C | | |
| 4 | Temp. cycle 3 | ± 2.0 | | (30 min \times 100 cycle/each) | | |
| 5 | Resistance to Soldering heat (Reflow characteristics) | ± 1.0 | Satisfy Item | Reflow furnace with the condition 2 times | | |
| 6 | Drop | ± 2.0 | test | Free drop from 750 mm height on a hard wooden board for 3 times. (Board is thickness more than 30 mm) | | |
| 7 | Vibration (variable frequency) | ± 1.0 | | 10 Hz to 55 Hz 0.75 mm 55 Hz to 500 Hz acceleration 98 m/s ² 10 Hz \rightarrow 500 Hz \rightarrow 10 Hz 15 min./cycle 6 h(2 h × 3 directions) | | |
| 8 | ESD (MM) | ± 1.0 | | 200pF 0Ω 200V. Discharge 3 pulses | | |
| 9 | ESD (HBM) | ± 1.0 | | 100pF 1.5k Ω 2000V. Discharge 3 pulses | | |
| 10 | Solderability Terminals must be 95 % covered with fresh solder | | Dip termination into solder bath at +235 °C for 5 s (Using Rosin Flux) | | | |

(The company evaluation condition. we evaluate it by the following examination item and examination condition.)

Notes

1.*1 each test is independent.

2.*2 measuring 2 h to 24 h later leaving in room temperature after each test.

3.*3 Pre conditionings

1. reflow 2 times

2. Initial value shall be after 24 h at room temperature.

Infrared-reflow

Pre heating temperature: +170 °CHeating temperature: +220 °CPeak temperature must not exceed +260 °C

Pre heating time : 100 s Heating time : 35 s



[8] Dimensions And Marking Layout



(unit : mm)

| Dim. | Min. | Тур. | Max. | Dim. | Min. | Тур. | Max. |
|------|------|------|------|------|------|-------|------|
| W | 2.35 | 2.50 | 2.65 | D | 0.40 | 0.50 | 0.60 |
| L | 1.85 | 2.00 | 2.15 | E | 1.35 | 1.50 | 1.65 |
| Н | 0.70 | 0.80 | 0.90 | F | | C0.2 | |
| А | 1.35 | 1.50 | 1.65 | G | | R0.15 | |
| В | 1.95 | 2.10 | 2.25 | К | | 0.45 | |
| С | 0.50 | 0.60 | 0.70 | | | | |

[9] Recommendable patterning

For actual design work, please consider optimum condition together with mounting density, reliability of soldering and mount ability etc.

Do not design any patterns except GND on the shaded area.

Soldering position



Unit: mm

[10] Handling precautions

Prior to using this product, please carefully read the section entitled "Precautions" on our Web site (<u>http://www.epsontoyocom.co.jp/english/support/support.html</u>) for instructions on how to handle and use the product properly to ensure optimal performance of the product in your equipment. Before using the product under any conditions other than those specified therein, please consult with us to verify and confirm that the performance of the product will not be negatively affected by use under such conditions.

In addition to the foregoing precautions, in order to avoid the deteriorating performance of the product, we strongly recommend that you <u>DO NOT</u> use the product under <u>ANY</u> of the following conditions:

- (1) Mounting the product on a board using water-soluble solder flux and using the product without removing the residue of the flux completely from the board. The residue of such flux that is soluble in water or water-soluble cleaning agent, especially the residues which contains active halogens, will negatively affect the performance and reliability of the product.
- (2) Using the product in any manner that will result in any shock or impact to the product.
- (3) Using the product in places where the product is exposed to water, chemicals, organic solvent, sunlight, dust, corrosive gasses, or other materials.
- (4) Using the product in places where the product is exposed to static electricity or electromagnetic waves.
- (5) Applying ultrasonic cleaning without advance verification and confirmation that the product will not be affected by such a cleaning process, because it may damage the crystal, IC and/or metal line of the product.
- (6) Touching the IC surface with tweezers or other hard materials directly.
- (7) Using the product under any other conditions that may negatively affect the performance and/or reliability of the product.
- (8) Using the product with power line ripple exceeding 200 mV(p-p) level.

Should any customer use the product in any manner contrary to the precautions and/or advice herein, such use shall be done at the customer's own risk.

TAPING SPECIFICATION

. Application

This standard will apply to 2.5×2.0 Ceramic package. Spec : CG package

. Contents

| Item No. | Item | Page |
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| [1] | Taping specification | 1 to 2 |
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| [3] | Shipping carton | |
| [4] | Marking | 4 |
| [5] | Quantity | |
| [6] | Storage environment | |
| [7] | Handling | |





Start & end point



| Iter | Empty space | |
|--------------|--------------|-------------|
| Tape leader | Top tape | Min. 200 mm |
| | Empty pocket | Min. 150 mm |
| Tape trailer | Top tape | Min. 0 mm |
| Empty pocket | | Min. 150 mm |

P. 2

[2] Inner carton

a) Packing to alumi laminate bag

The reel is packed in the vacuum with the alumi laminate bag.



b) Packing to inner carton



[3] Shipping carton



[4] Marking

- (1) Reel marking
 - Reel marking shall consist of :
 - 1) Parts name
 - 2) Quantity
 - 3) Manufacturing date or symbol
 - 4) Manufacturer's name or symbol
 - 5) Others (if necessary)
- (2) Inner carton marking
 - Same as reel marking.
- (3) Shipping carton marking
 - Shipping carton marking shall consist of :
 - 1) Parts name
 - 2) Quantity
- [5] Quantity
 - Max : 2000 pcs/reel Min : 500 pcs/reel

[6] Storage environment

- (1) To storage the reel at 15 °C to 35 °C, 25 %RH to 85 %RH of humidity.
- (2) To open the packing just before using.
- (3) Not to expose the sun.
- (4) Not to storage with some erosive chemicals.
- (5) Nothing is allowed to put on the reel or carton to prevent mechanical damage.

[7] Handling

• To handle with care to prevent the damage of tape, reel and products.

| - PROCESS QUALITY (| CONTROL - | | | | | '13.03.28 | Approved | Checked Prepared |
|-------------------------------|---|-----|---|---|--|--|-----------------------------------|--|
| <u>No. TG5006CG - 00 – AV</u> | <u>'E - 1 CRYSTAL OSCILLA'</u> | TOR | : TG-5006CG | | SEI Timing | KO EPSON CORP. Device Business Unit | H.koike | H.suzuki |
| Manufacturi | ng process chart | No. | Section In Charge | Standards | Inspection, Control Item | Instruments | Inspection Methods | Record |
| Au Wire | IC Wafer | 1 | ETSZ Quality Assurance | Purchase specification | Appearance | Visual inspection | Every lot | Data sheet |
| | 1 Inspection | 2 | ETSZ Producion Department | Specification (Work standard) | Heater temperature Bump dimension | Thermometer Microscope | Daily Sampling | Daily check sheet Data sheet |
| | | 3 | ETSZ Producion Department | Specification | Shear strength Cutting condition | Bond tester Visual inspection | Sampling | Data sheet Daily check sheet |
| - | - 2 Bump Bonding | 4 | ETSZ Produción Department | (Work standard) | Appearance | Built in gauge | Every batch | Tool change check sheet |
| | 3 Tape mounting | - | ETSZ Producton Department | (Work standard) | Weter resister | Duilt in mater | | |
| | (4) Dicing | 5 | ETSZ Producion Department | (Work standard) | water resistance | Built-in meter | Daily | Daily check sheet |
| Crystal Unit | 5 Wafer Cleaning | 6 | ETSZ Producion Department | (Work standard) | Dicing condition | Microscope | Sampling | Data sheet |
| \bigtriangledown | 6 Appearance Inspection | 7 | ETSZ Producion Department | Specification (Work standard) | UV condition | UV intensity meter | Daily | Daily check sheet |
| | T UV irradiation | 8 | ETSZ Producion Department | Specification (Work standard) | Flow rate of O2 and Ar | Built-in meter | Daily | Daily check sheet |
| 8 Plasma etching | | 9 | ETSZ Producion Department | Specification (Work standard) | Number of US tool shots Number of ejector needle shot. Heater temperature | Built-in counter Built-in counter Thermometer | 100% 100% Daily | Tool change check sheet Daily check sheet Data sheet |
| | 9 Flip chip bonding | | | | Shear strength | Microscope Bond tester | Sampling Sampling | Data sheet |
| | Ţ | 10 | ETSZ Producion Department | Specification (Work standard) | Flipchip bonding Condition | Microscope | Sampling | Data sheet |
| | Appearance inspection | 11 | ETSZ Producion Department | Specification (Work standard) | Chip coat storage temp. Pot lifetime | Thermometer Built-in timer | Daily 100% | Daily check sheet Tool change check sheet |
| | 11 Under fill filling | 12 | ETSZ Producion Department | Specification (Work standard) | Curing time Oven temperature | Timer Thermometer | Every batch Daily | Data sheet Daily check sheet |
| | (12) Curing | 13 | ETSZ Producion Department | Specification (Work standard) | Appearance (FC & Under fill condition) | Microscope | 100% Inspection | Data sheet |
| | Appearance inspection | 14 | ETSZ Producion Department | Specification (Work standard) | Reflow profile | Thermometer | Daily | Daily check sheet |
| | | 15 | ETSZ Producion Department | Specification (Work standard) | Stage temperature | Thermometer | Daily | Daily check sheet |
| | (14) Renow | 16 | ETSZ Producion Department | Specification (Work standard) | Stage temperature | Thermometer | Daily | Daily check sheet |
| | 15 1st Temp. characteristic test | 17 | ETSZ Producion Department | Specification (Work standard) | Stage temperature | Thermometer Frequency counter | Daily | Daily check sheet |
| Consistent equipment | ROM writing Temperature characteristic | 18 | ETSZ Producion Department | (Work standard) Specification (Work standard) | Frequency, Output-level Current drain, Frequency co ntrol range Master confirmation | Multi-meter Freq. counter Oscilloscope | 100% Inspection | Data sheet |
| | inspection | 19 | ETSZ Producion Department | Specification (Work standard) | Appearance Marking | CCD camera | 100% Inspection | Data sheet |
| | Electrical characteristic inspection | 20 | ETSZ Producion Department | Specification (Work standard) | Peeling off strength Direction | Peel back tester Visual inspection | Daily Sampling Delivery lot | Daily check sheet Data sheet |
| Consistent equipment | 19 Marking | 21 | ETSZ Quality Assurance Department | Specification (Work standard) | Frequency, Current drain, Appearance, Dimension | Freq. counter,Multi-met er, Visual inspection Calipers | Sampling | Data sheet |
| | (20) Taping | 22 | Production Control Department (ETSZ & Ina Plant) | Specification (Work standard) | Quantity | Visual inspection | Sampling Delivery lot | Data sheet Delivery record |
| | 21 Out going inspection | | | | | | | |
| | (22) Packaging & Shinning | | | | | | | |
| | | | | | | | | |
| | | | | | | | | |
| | | | | | | | | |
| | | | | | | | | |
| | | | | | | | | |
| | | | | | | | | |



RELIABILITY TEST DATA **Product Name : TG-50xxCG series**

The Company evaluation condition

We evaluate environmental and mechanical characteristics by the following test condition . OUT10-E31-40M

| | | | VAI | TEST | FAIL | |
|-----|--------------------------------|--|---|---------------------------------------|-------|-------|
| No. | ITEM | TEST CONDITIONS | $\Delta f / f *2$ | Electrical | Qty | Qty |
| | | | $[1 \times 10^{-6}]$ | characteristics | [n] | [n] |
| 1 | High temperature storage | +85 °C × 1 000 h | *3 ± 2.0 | Satisfy output level after test | 22 | 0 |
| 2 | Low temperature storage | -40 $^{\rm o}{\rm C}\times1$ 000 h | *3 ± 2.0 | | 22 | 0 |
| 3 | High Temperature with Humidity | $+85\pm2~^{o}C\times85\pm5~\%RH\times1~000~h$ | *3 ± 2.0 | | 22 | 0 |
| 4 | Temperature cycle | -40 °C +85 °C 30 min at each temp. 1000 cycles | *3 ± 2.0 | | 22 | 0 |
| 5 | Resistance to soldering heat | Convection reflow soldering furnace (3 times) | ± 1.0 | | 22 | 0 |
| 6 | Drop | 150g dummy jig (Epson Toyocom Standard) drop from 1500 mm height on the concrete 6 directions 3 times. | ± 2.0 | | 22 | 0 |
| 7 | Vibration | 10 Hz to 55 Hz amplitude 0.75 mm 55 Hz to 500 Hz acceleration 98 m/s^2 10 Hz 500 Hz 10 Hz 15 min / cycle 6 h (2 h × 3 directions) | ± 2.0 | | 22 | 0 |
| 8 | ESD (MM) | $200 pF0\Omega\;200V$, Discharge 3 pulses | ± 1.0 | | 22 | 0 |
| 9 | ESD (HBM) | 100pF 1.5kΩ 2000V , Discharge 3 pulses | ± 1.0 | | 22 | 0 |
| 10 | Solderability | Dip termination into solder bath at +235 $^{\circ}C \pm 5 ^{\circ}C$ for 5 s (Using Rosin Flux) | Termination must be covered with fresh solder more than 95 % of dip area. | | 11 | 0 |

Notes

1. *1 Each test done independently.

2. *2 Measuring 2 h to 24 h later leaving in room temperature after each test.

3. *3 Initial value shall be measured after 24 h storage at room temperature Pre-treatment

Pre-treatment : Bake (+125 \times 24 h) Moisture soak (+85 \times 60 % \times 168 h) reflow (3 times)



Product Name : TG-50xxCG series



•Electro Static Discharge

Product Name :TG-5006CG series LEVEL :H1C

| No. | Item | Test term | Test Quy [n] | Result |
|-----|------------------|---|-----------------|--------|
| 1 | Machine Model | EIAJ ED-4701-1 C111 200 pF, 0 Ω, 1 time ElectroStatic Discharge:±200V | 5 | ОК |
| 2 | Human Body Model | EIAJ ED-4701-1 C111A 100 pF,1.5 KΩ, 3 time ElectroStatic Discharge:±2000V | 5 | ОК |

Machine Model



No problem to 200V

Human Body Model



No problem to 2000V